## **Notice of References Cited**

Application/Control No.

Applicant(s)/Patent Under Reexamination
LEE, JONG-HWAN

Examiner

Conrad J. DeWitte

Applicant(s)/Patent Under Reexamination
LEE, JONG-HWAN

Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,774,096 A	06-1998	Usuki et al.	345/8
	В	US-6,266,041 B1	07-2001	Cairns et al.	345/100
	C ·	US-6,448,944 B2	09-2002	Ronzani et al.	345/8
	D	US-5,751,259 A	05-1998	lwamoto, Kazuyo	345/8
	Е	US-6,545,650 B1	04-2003	Yamada et al.	345/7
	F	US-6,535,183 B2	03-2003	Melville et al.	345/8
	G	US-6,532,008 B1	03-2003	Guralnick, Brian	345/419
	Н	US-6,518,939 B1	02-2003	Kikuchi, Kumi	345/8
	1	US-6,160,666 A	12-2000	Rallison et al.	359/630
	J	US-6,144,347 A	11-2000	Mizoguchi et al.	345/8
	К	US-5,880,773 A	03-1999	Suzuki, Yoshiaki	348/115
	L	US-5,347,400 A	09-1994	Hunter, Ken	359/815
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	W	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.